

Applications

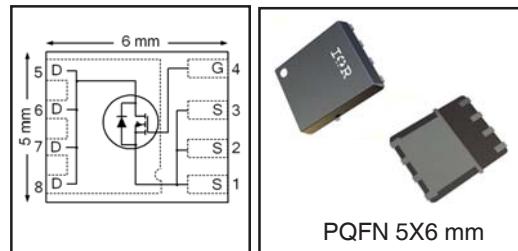
- Synchronous MOSFET for Notebook Processor Power
- Synchronous Rectifier MOSFET for Isolated DC-DC Converters in Networking Systems

HEXFET® Power MOSFET

V_{DSS}	R_{DS(on)} max	Q_g
30V	4.8mΩ@V_{GS} = 10V	17nC

Benefits

- Very low R_{DS(ON)} at 4.5V V_{GS}
- Low Gate Charge
- Fully Characterized Avalanche Voltage and Current
- 100% Tested for R_G
- Lead-Free (Qualified up to 260°C Reflow)
- RoHS compliant (Halogen Free)
- Low Thermal Resistance
- Large Source Lead for more reliable Soldering



Absolute Maximum Ratings

	Parameter	Max.	Units
V _{DS}	Drain-to-Source Voltage	30	V
V _{GS}	Gate-to-Source Voltage	± 20	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	20	A
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V	16	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	54	
I _{DM}	Pulsed Drain Current ①	160	
P _D @ T _A = 25°C	Power Dissipation ⑤	3.1	W
P _D @ T _A = 70°C	Power Dissipation ⑤	2.0	
	Linear Derating Factor ⑤	0.025	W/°C
T _J	Operating Junction and	-55 to + 150	°C
T _{STG}	Storage Temperature Range		

Thermal Resistance

	Parameter	Typ.	Max.	Units
R _{θJC}	Junction-to-Case ④	—	5.6	°C/W
R _{θJA}	Junction-to-Ambient ⑤	—	40	

Notes ① through ⑤ are on page 9

Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	30	—	—	V	$V_{\text{GS}} = 0\text{V}$, $I_D = 250\mu\text{A}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.022	—	V/ $^\circ\text{C}$	Reference to 25°C , $I_D = 1\text{mA}$
$R_{\text{DS}(\text{on})}$	Static Drain-to-Source On-Resistance	—	4.1	4.8	$\text{m}\Omega$	$V_{\text{GS}} = 10\text{V}$, $I_D = 20\text{A}$ ③
		—	6.0	6.8		$V_{\text{GS}} = 4.5\text{V}$, $I_D = 16\text{A}$ ③
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	1.35	1.8	2.35	V	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = 50\mu\text{A}$
$\Delta V_{\text{GS}(\text{th})}$	Gate Threshold Voltage Coefficient	—	-6.3	—	mV/ $^\circ\text{C}$	
I_{DSS}	Drain-to-Source Leakage Current	—	—	1.0	μA	$V_{\text{DS}} = 24\text{V}$, $V_{\text{GS}} = 0\text{V}$
		—	—	150		$V_{\text{DS}} = 24\text{V}$, $V_{\text{GS}} = 0\text{V}$, $T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{\text{GS}} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-100		$V_{\text{GS}} = -20\text{V}$
g_{fs}	Forward Transconductance	48	—	—	S	$V_{\text{DS}} = 15\text{V}$, $I_D = 16\text{A}$
Q_g	Total Gate Charge	—	17	26	nC	$V_{\text{DS}} = 15\text{V}$ $V_{\text{GS}} = 4.5\text{V}$ $I_D = 16\text{A}$ See Fig.17 & 18
$Q_{\text{gs}1}$	Pre-Vth Gate-to-Source Charge	—	4.5	—		
$Q_{\text{gs}2}$	Post-Vth Gate-to-Source Charge	—	2.0	—		
Q_{gd}	Gate-to-Drain Charge	—	5.5	—		
Q_{godr}	Gate Charge Overdrive	—	5.0	—		
Q_{sw}	Switch Charge ($Q_{\text{gs}2} + Q_{\text{gd}}$)	—	7.5	—	nC	$V_{\text{DS}} = 16\text{V}$, $V_{\text{GS}} = 0\text{V}$
Q_{oss}	Output Charge	—	9.0	—		
R_G	Gate Resistance	—	1.5	2.3		
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	—	17	—	ns	$V_{\text{DD}} = 15\text{V}$, $V_{\text{GS}} = 4.5\text{V}$ $I_D = 16\text{A}$ $R_G = 1.8\Omega$ See Fig.15
t_r	Rise Time	—	12	—		
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time	—	19	—		
t_f	Fall Time	—	7.0	—		
C_{iss}	Input Capacitance	—	2360	—	pF	$V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 15\text{V}$ $f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	450	—		
C_{rss}	Reverse Transfer Capacitance	—	210	—		

Avalanche Characteristics

	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy ②	—	28	mJ
I_{AR}	Avalanche Current ①	—	16	A

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_s	Continuous Source Current (Body Diode)	—	—	3.9	A	MOSFET symbol showing the integral reverse p-n junction diode.
	Pulsed Source Current (Body Diode) ①	—	—	160		
V_{SD}	Diode Forward Voltage	—	—	1.0	V	$T_J = 25^\circ\text{C}$, $I_S = 16\text{A}$, $V_{\text{GS}} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	14	21	ns	$T_J = 25^\circ\text{C}$, $I_F = 16\text{A}$, $V_{\text{DD}} = 15\text{V}$
Q_{rr}	Reverse Recovery Charge	—	15	23	nc	$dI/dt = 300\text{A}/\mu\text{s}$ ③ See Fig.16
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

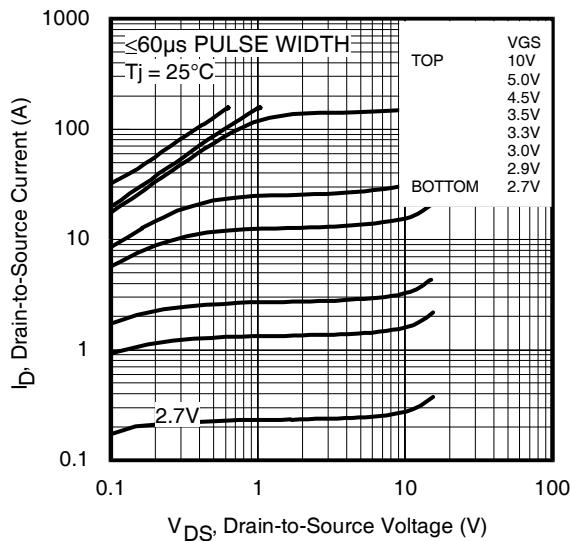


Fig 1. Typical Output Characteristics

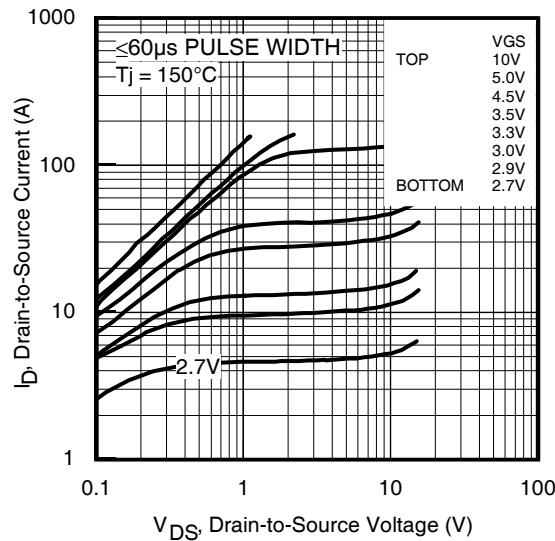


Fig 2. Typical Output Characteristics

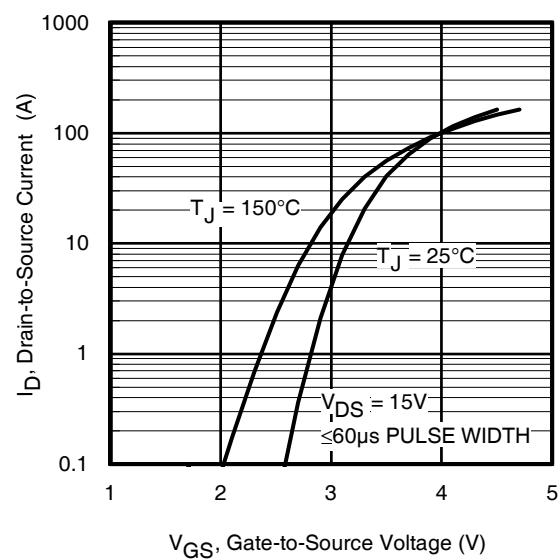


Fig 3. Typical Transfer Characteristics

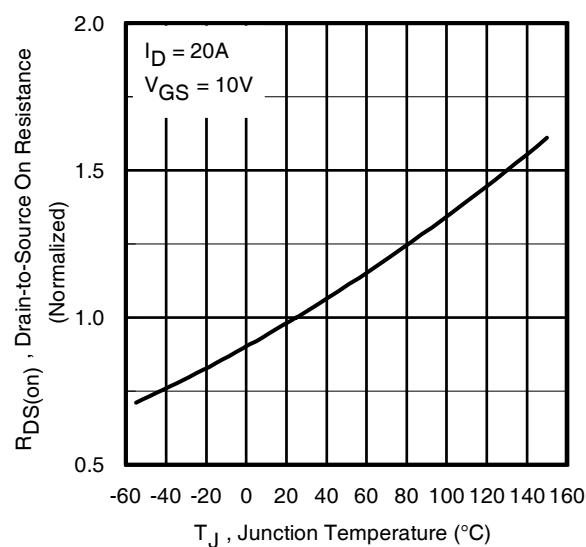


Fig 4. Normalized On-Resistance
vs. Temperature

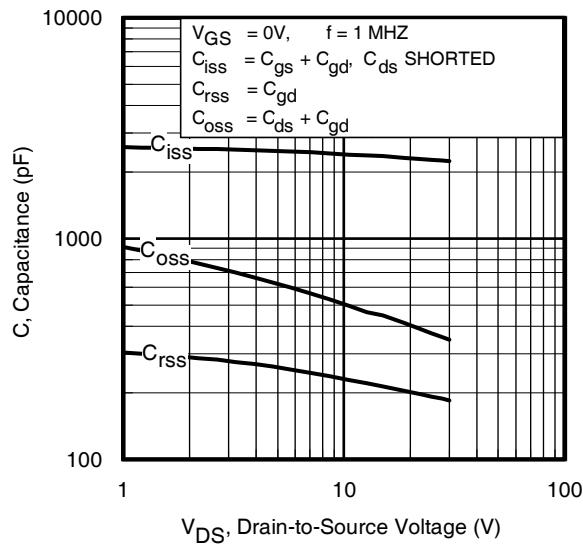


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

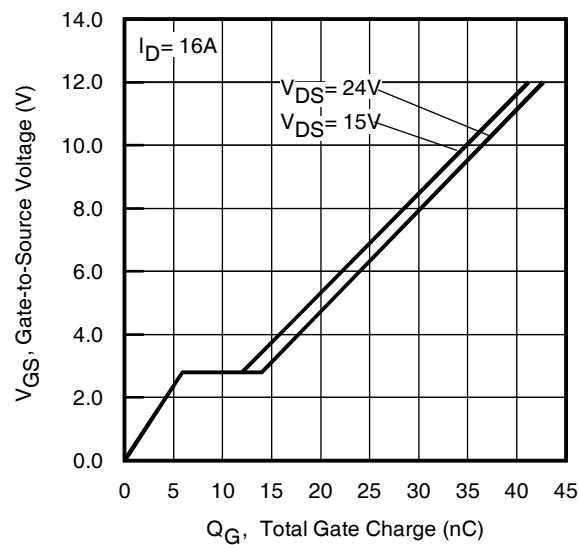


Fig 6. Typical Gate Charge vs.
Gate-to-Source Voltage

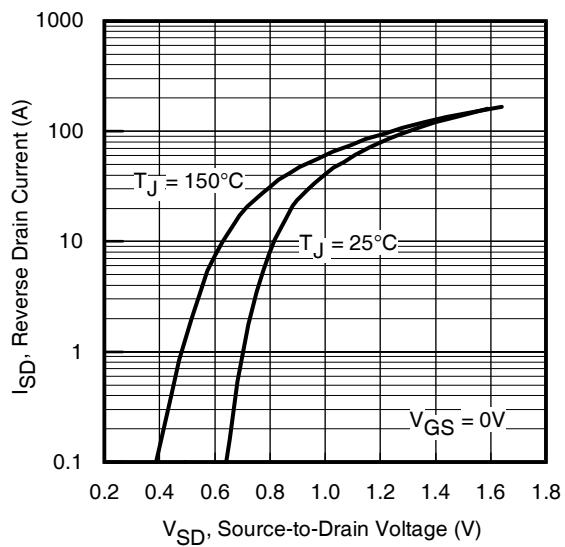


Fig 7. Typical Source-Drain Diode
Forward Voltage

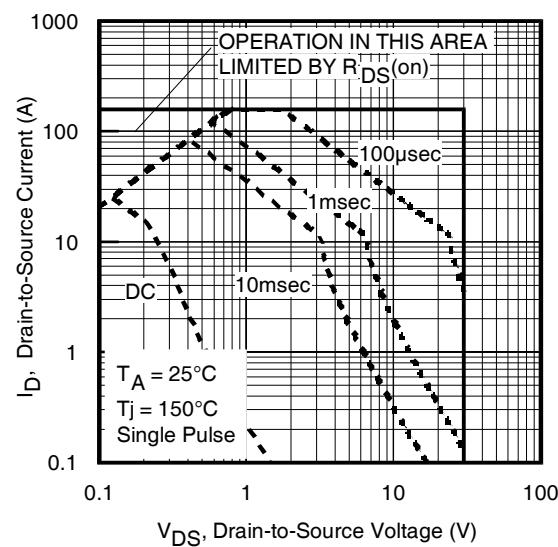


Fig 8. Maximum Safe Operating Area

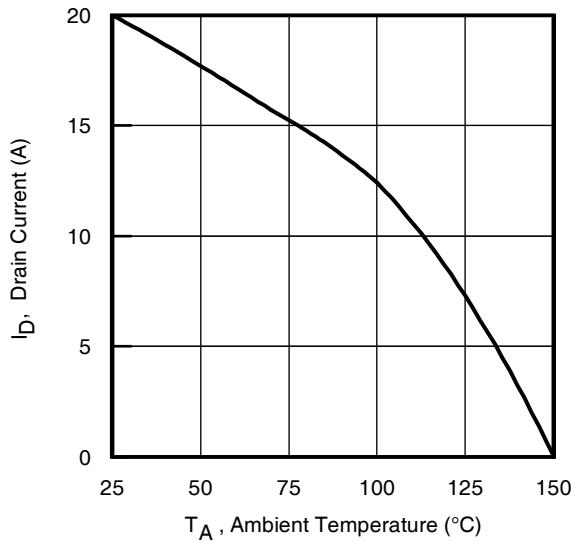


Fig 9. Maximum Drain Current vs.
Ambient Temperature

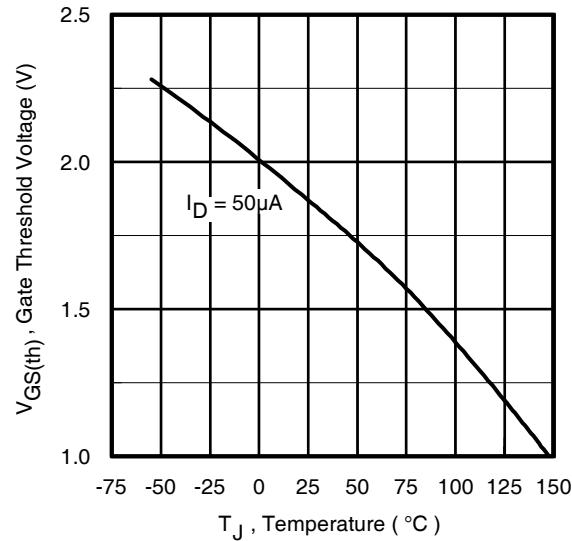


Fig 10. Threshold Voltage vs. Temperature

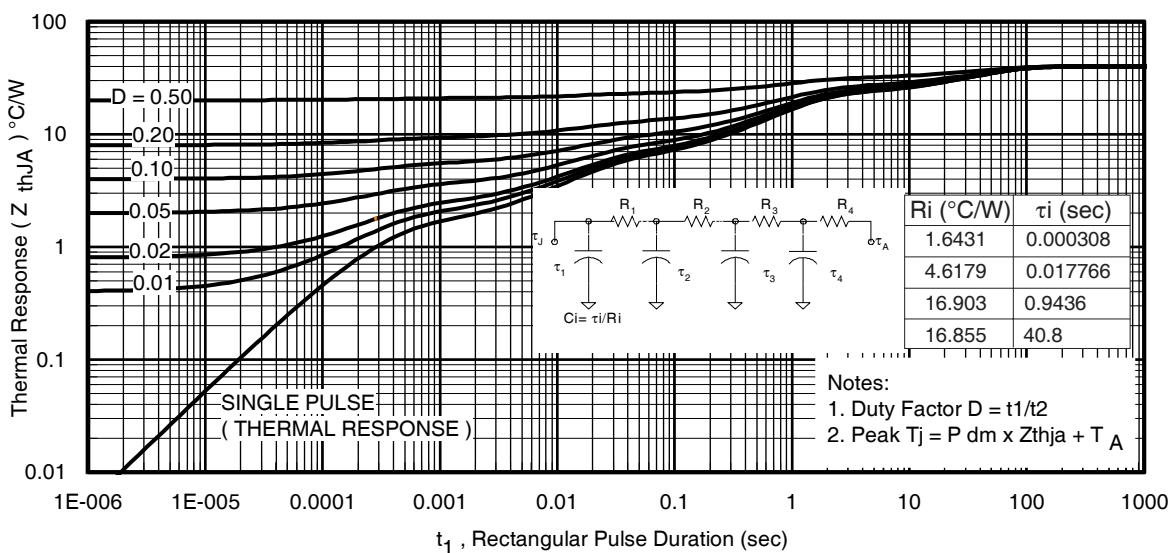


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

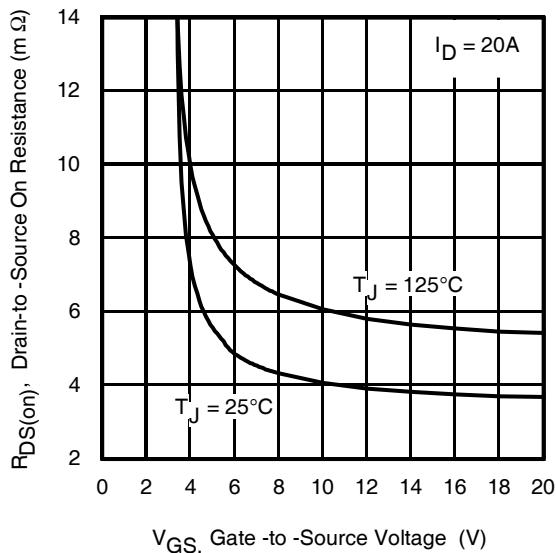


Fig 12. On-Resistance vs. Gate Voltage

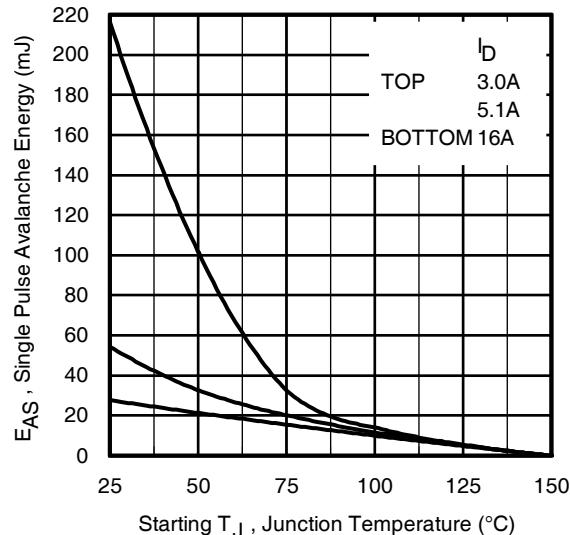


Fig 13. Maximum Avalanche Energy vs. Drain Current

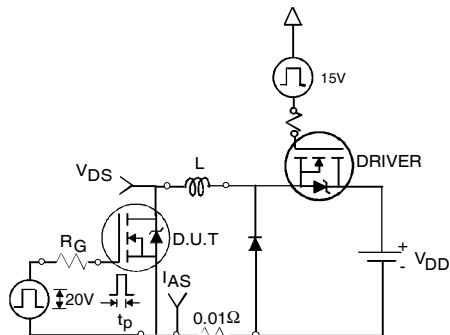


Fig 14a. Unclamped Inductive Test Circuit

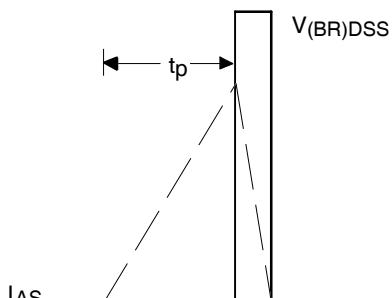


Fig 14b. Unclamped Inductive Waveforms

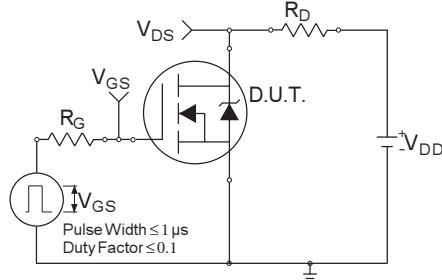


Fig 15a. Switching Time Test Circuit

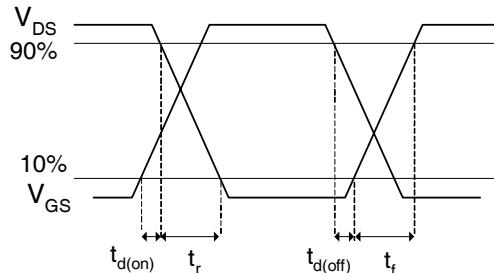


Fig 15b. Switching Time Waveforms

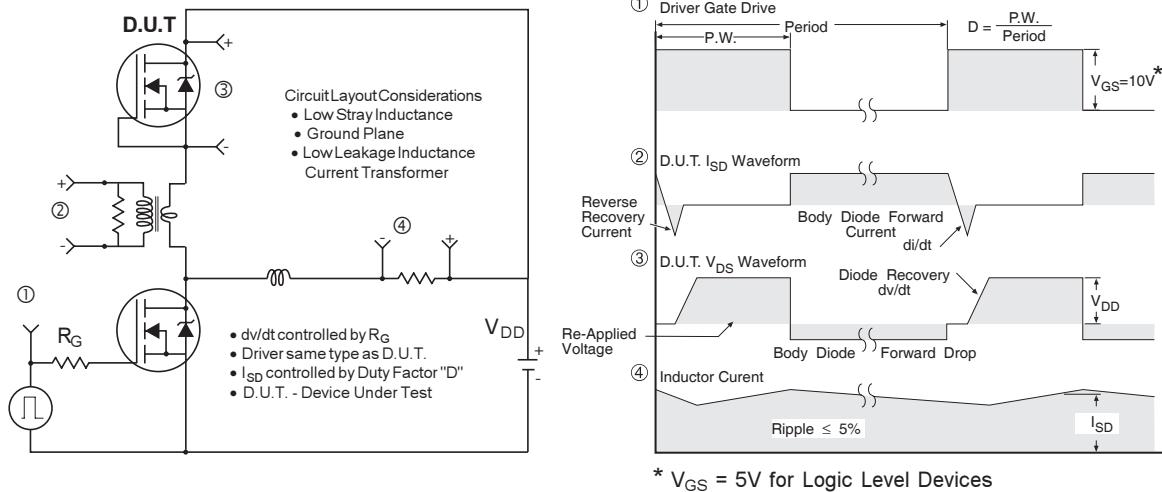


Fig 16. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

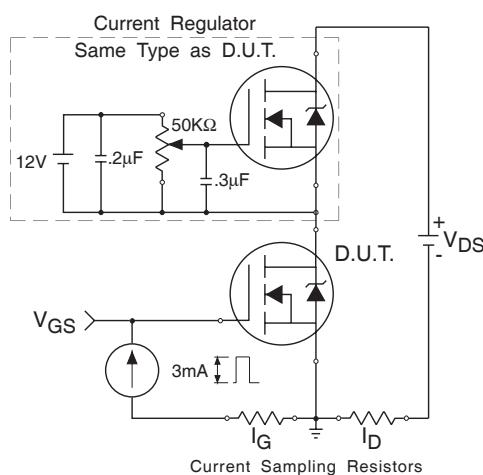


Fig 17. Gate Charge Test Circuit

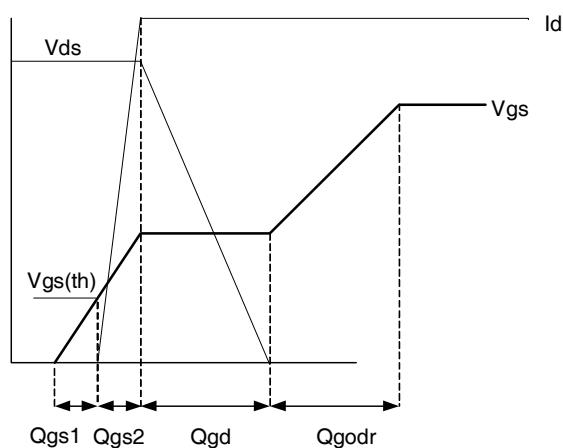
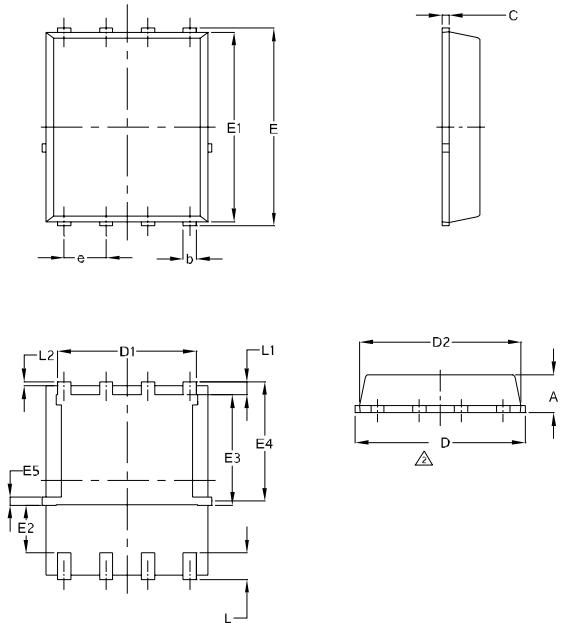


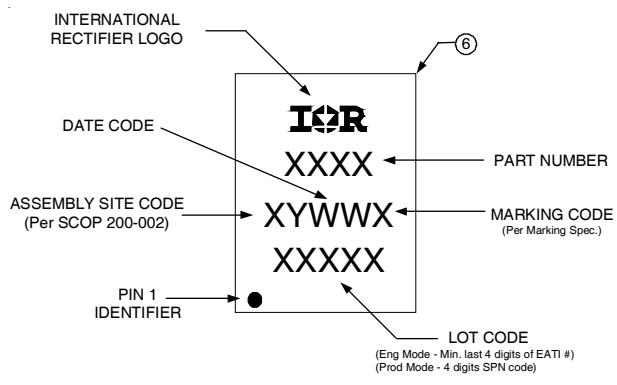
Fig 18. Gate Charge Waveform

PQFN 5x6 Option "E" Package Details



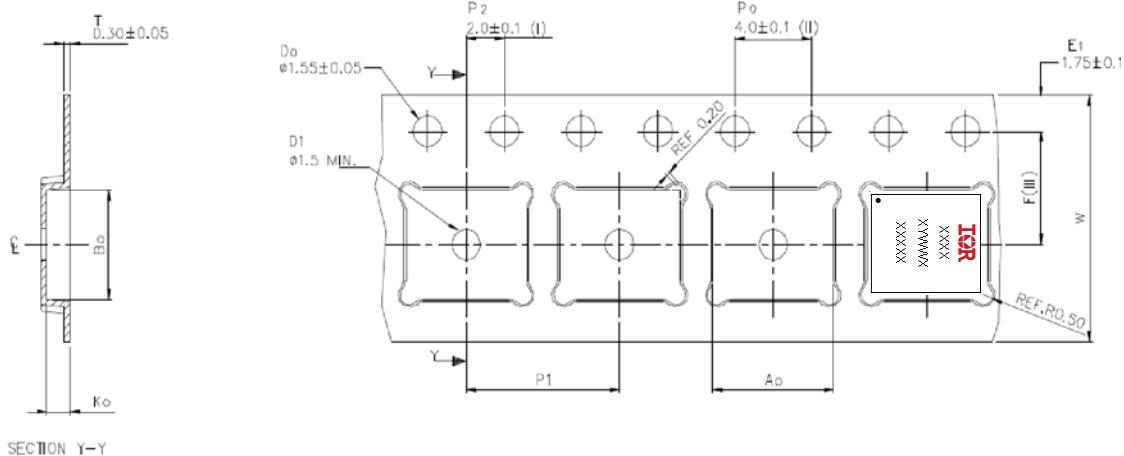
SYMBOL	COMMON			
	MM		INCH	
	MIN.	MAX.	MIN.	MAX.
A	0.90	1.17	0.0354	0.0461
b	0.31	0.51	0.0130	0.0189
C	0.195	0.300	0.0077	0.0118
D	4.80	5.25	0.1890	0.2028
D1	3.91	4.31	0.1539	0.1697
D2	4.80	5.10	0.1890	0.1968
E	5.90	6.25	0.2323	0.2421
E1	5.65	6.15	0.2224	0.2362
E2	1.10	—	0.0594	—
E3	3.32	3.78	0.1307	0.1480
E4	3.52	3.72	0.1346	0.1409
E5	0.13	0.32	0.0071	0.0126
e	1.27	BSC	0.050	BSC
L	0.51	0.86	0.0020	0.0098
L1	0.38	0.71	0.0150	0.0260
L2	0.05	0.25	0.0201	0.0339
I	0	0.18	0	0.0071

PQFN Part Marking



Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

PQFN Tape and Reel



A ₀	6.30 +/− 0.1
B ₀	5.30 +/− 0.1
K ₀	1.20 +/− 0.1
F	5.50 +/− 0.1
P ₁	8.00 +/− 0.1
W	12.00 +/− 0.3

- (I) Measured from centreline of sprocket hole to centreline of pocket.
- (II) Cumulative tolerance of 10 sprocket holes is ± 0.20 .
- (III) Measured from centreline of sprocket hole to centreline of pocket.
- (IV) Other material available.
- (V) Typical SR of form tape Max 10^9 OHM/SQ

ALL DIMENSIONS IN MILLIMETRES UNLESS OTHERWISE STATED

Note: For the most current drawing please refer to IR website at <http://www.irf.com/package/>

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25^\circ\text{C}$, $L = 0.22\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 16\text{A}$.
- ③ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ④ R_{thjc} is guaranteed by design
- ⑤ When mounted on 1 inch square 2 oz copper pad on 1.5x1.5 in. board of FR-4 material.

Revision History

Date	Comments
08/08/2013	<ul style="list-style-type: none"> • Updated the package drawing, on page 1. • Updated the package outline drawing, on page 8. • This drawing change is related to PCN "Hana-GTBF-GEM 5x6 PQFN Public."

International
IR Rectifier

IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA
To contact International Rectifier, please visit <http://www.irf.com/whoto-call/>